-	Form PT	D-1449 (Modified)	Atty Docket No.			Serial No.								
	LIST OF PATENTS AND PUBLICATIONS					H1559 10/790,457								
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Information Disclosure Statement PTO-1449 (Modified)

Se identification of any reference is not intended to be, and should not be understood as being, an admission that such publication, in fact, constitutes "prior any within the meaning of applicable law since, for example, a given reference may have a later effective date than first seems apparent or the reference may have a later effective date which can be antedated. The "prior art" status of any reference is a matter to be resolved during prosecution.

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